NOV 2 6 2003

Information Disclosure
Statement By Applicant

(Use Several Sheets if Necessary)

Atty. Docket No. NVIDP234/P000825

NVIDP234/P000825 Applicant:

Singh et al. Filing Date:

7/31/2003

Application No.:

10/633,004

Group Art Unit:

Unassigned ZSI

U.S. Patent Documents

Examiner					T T	Sub-	Filing
Initial	No.	Patent No.	Date	Patentee	Class	class	Date
Vu	Α	6,538,326	03/25/2003	Shimizu et al.	257	758	10/4/2001
1	В	6,552,438	04/22/2003	Lee et al.	257	784	12/21/2000
	С	5,965,903	10/12/1999	Chittipeddi et al.	257	48	02/12/1998
	D	6,297,562	10/02/2001	Tilly	257	780	09/20/1999
	Е	6,232,662	05/15/2001	Saran	257	750	07/02/1999
	F	6,365,970	04/02/2002	Tsai et al.	257	751	12/10/1999
	G	6,417,087	07/09/2002	Chittipeddi et al.	438	612	12/16/1999
	H	4,636,832	01/13/1987	Abe et al.	357	68	03/04/1986
	I	4,723,197	02/02/1988	Takiar et al.	361	403	12/16/1985
	J	6,100,589	08/08/2000	Tanaka	257	758	08/19/1997
	K	4,984,061	01/08/1991	Matsumoto	357	68	05/10/1988
	L	6,384,486	05/07/2002	Zuniga et al.	257	781	12/10/1999
	M	6,400,026	06/04/2002	Andou et al.	257	771	06/26/2000
	N	6,489,228	12/03/2002	Vigna et al.	438	612	10/02/2000
	0	6,358,831	03/19/2002	Liu et al.	438	612	03/03/1999
	P	5,965,903	10/12/1999	Chittipeddi et al.	257	48	02/12/1998
	Q	6,037,668	03/14/2000	Cave et al.	257	784	11/13/1998
	R	6,313,537	11/06/2001	Lee et al.	257	758	11/09/1998
	S	5,773,899	06/30/1998	Zambrano	257	784	08/29/1996
	T	6,144,100	11/07/2000	Shen et al.	257	762	10/28/1997
Vin	U	5,751,065	05/12/1998	Chittipeddi et al.	257	758	10/30/1995

Other Documents

Examiner	NI	Author Title Date Place (a.g. Jo	aymal) of Publication		
Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication			
	V	Heinen, Gail et al., "Wire Bonds (Over Active Circuits", 1994, IEEE		
*	W	Level Cu Metal, FSG Low-K Inter 2001, IEEE	euits Under Wire Bonding I/O Pads in 0.13 μm Eight- r-Metal Dielectric CM OS Technology +", October		
*	X	Efland, T., et al., "LeadFrameOnt Active Circuit", 2001, Internation ICs, Osaka	Chip offers Integrated Power Bus and Bond over al Symposium on Power Semiconductor Devices &		
Examiner	HUNG VU		Date Considered 10/05/04		

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

HOV 2 6 2003 25 JE

Form 1449 (Modified)

Information Disclosure Statement By Applicant

(Use Several Sheets if Necessary)

Atty. Docket No. NVIDP234/P000825

Applicant: Singh et al.

Filing Date: 7/31/2003

Application No.:

10/633,004

Group Art Unit: Unassigned 고영(

U.S. Patent Documents

			U.S. Pati	ent Documents			
Examiner						Sub-	Filing
Initial	No.	Patent No.	Date	Patentee	Class	class	Date
Vin	Y	6,448,641	09/10/2002	Ker et al.	257	700	06/09/1999
i	Z	6,486,051	11/26/2002	Sabin et al.	438	612	03/17/1999
	AA	6,489,688	12/03/2002	Baumann et al.	257	786	05/02/2001
,	BB	6,087,732	07/11/2000	Chittipeddi et al.	257	786	09/28/1998
	CC	5,027,188	06/25/1991	Owada et al.	357	68	09/13/1989
	DD	6,329,712	12/11/2001	Akram et al.	257	700	03/25/1998
	EE	5,986,343	11/16/1999	Chittipeddi et al.	257	758	05/04/1998
Vin	FF	6,016,000	01/18/2000	Moslehi	257	522	04/22/1998
	GG					. /	
	НН						1
	II					1	
	JJ						
	KK						
	LL						
	MM						
	NN						
	00						
	PP				1		
	QQ		1				
	RR			·			
	SS		Ì			1	
		*		<u> </u>		·	

Other Documents

Examiner					
Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication			
N _m J		Saran, Mukul et al., "Elimination of Bond-pad Damage Through Structural Reinforcement of Intermetal Dielectrics", 1998, IEEE 36th Annual International Reliability Physics Symposium, Reno, Nevada			
Examiner	•	HUNG- VU Date Considered W 05/04-			

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.